

<b>Notice of References Cited</b>	Application/Control No. 10/717,715	Applicant(s)/Patent Under Reexamination AOKI ET AL.	
	Examiner Brian P. Mruk	Art Unit 1751	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B	US-6,440,856	08-2002	Bessho et al.	438/691
	C	US-			
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	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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*	N	JP 2000-219900	08-2000	Japan	Satoshi et al	C11D 17/08
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	S					
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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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*Brian P. Mruk*

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